

RADIO TEST REPORT

Test Report No. 15738317H-A-R1

Customer	Panasonic Corporation of North America
Description of EUT	BLE UNIT
Model Number of EUT	HU500030C
FCC ID	ACJ932HU500030C
Test Regulation	FCC Part 15 Subpart C
Test Result	Complied
Issue Date	September 16, 2025
Remarks	-

Representative Test Engineer



Yuta Moriya
Engineer

Approved By



Shinichi Miyazono
Leader



CERTIFICATE 5107.02

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 There is no testing item of "Non-accreditation".

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- For any test report referred in this report, the latest version (including any revisions) is always referred to.
- If the latest version is a revision, it replaces the previous version. See the table below for revisions and versions.

REVISION HISTORY

Revision	Test Report No.	Date	Page Revised Contents
- (Original)	15738317H-A	June 2, 2025	-
1	15738317H-A-R1	September 16, 2025	<p>Clause 2.1 Updated Test Date: March 24 to April 11, 2025 → March 24 to September 10, 2025</p> <p>Clause 3.2 Deleted reference standard: RSS-Gen Issue 5/Amendment 1/Amendment 2 for ISED</p> <p>Clause 3.3 Corrected Result of Conducted Emission: Complied → N/A</p> <p>Clause 4.2 Added the AC voltage for Item D in Block diagram</p> <p>SECTION 5 Deleted the 11.12.2.5.2 description from the IF Bandwidth section in the lower table. (page 11)</p> <p>APPENDIX 1 Retested and updated the data for Maximum Peak Output Power (page 17, 18)</p> <p>APPENDIX 2 Added Test Equipment for the test conducted on September 10, 2025</p>

Reference: Abbreviations (Including words undescribed in this report)

A2LA	The American Association for Laboratory Accreditation	IEC	International Electrotechnical Commission
AC	Alternating Current	IEEE	Institute of Electrical and Electronics Engineers
AFH	Adaptive Frequency Hopping	IF	Intermediate Frequency
AM	Amplitude Modulation	ILAC	International Laboratory Accreditation Conference
Amp, AMP	Amplifier	ISED	Innovation, Science and Economic Development Canada
ANSI	American National Standards Institute	ISO	International Organization for Standardization
Ant, ANT	Antenna	JAB	Japan Accreditation Board
AP	Access Point	LAN	Local Area Network
ASK	Amplitude Shift Keying	LIMS	Laboratory Information Management System
Atten., ATT	Attenuator	MCS	Modulation and Coding Scheme
AV	Average	MRA	Mutual Recognition Arrangement
BPSK	Binary Phase-Shift Keying	N/A	Not Applicable
BR	Bluetooth Basic Rate	NIST	National Institute of Standards and Technology
BT	Bluetooth	NS	No signal detect.
BT LE	Bluetooth Low Energy	NSA	Normalized Site Attenuation
BW	BandWidth	NVLAP	National Voluntary Laboratory Accreditation Program
Cal Int	Calibration Interval	OBW	Occupied Band Width
CCK	Complementary Code Keying	OFDM	Orthogonal Frequency Division Multiplexing
Ch., CH	Channel	OFDMA	Orthogonal Frequency Division Multiple Access
CISPR	Comite International Special des Perturbations Radioelectriques	P/M	Power meter
CW	Continuous Wave	PCB	Printed Circuit Board
DBPSK	Differential BPSK	PER	Packet Error Rate
DC	Direct Current	PHY	Physical Layer
D-factor	Distance factor	PK	Peak
DFS	Dynamic Frequency Selection	PN	Pseudo random Noise
DQPSK	Differential QPSK	PP	Preamble Puncturing
DSSS	Direct Sequence Spread Spectrum	PRBS	Pseudo-Random Bit Sequence
EDR	Enhanced Data Rate	PSD	Power Spectral Density
EIRP, e.i.r.p.	Equivalent Isotropically Radiated Power	QAM	Quadrature Amplitude Modulation
EMC	ElectroMagnetic Compatibility	QP	Quasi-Peak
EMI	ElectroMagnetic Interference	QPSK	Quadri-Phase Shift Keying
EN	European Norm	RBW	Resolution Band Width
ERP, e.r.p.	Effective Radiated Power	RDS	Radio Data System
EU	European Union	RE	Radio Equipment
EUT	Equipment Under Test	RF	Radio Frequency
Fac.	Factor	RMS	Root Mean Square
FCC	Federal Communications Commission	RSS	Radio Standards Specifications
FHSS	Frequency Hopping Spread Spectrum	Rx	Receiving
FM	Frequency Modulation	SA, S/A	Spectrum Analyzer
Freq.	Frequency	SG	Signal Generator
FSK	Frequency Shift Keying	SVSWR	Site-Voltage Standing Wave Ratio
GFSK	Gaussian Frequency-Shift Keying	TR	Test Receiver
GNSS	Global Navigation Satellite System	Tx	Transmitting
GPS	Global Positioning System	VBW	Video BandWidth
Hori.	Horizontal	Vert.	Vertical
ICES	Interference-Causing Equipment Standard	WLAN	Wireless LAN

CONTENTS	PAGE
SECTION 1: Customer Information	5
SECTION 2: Equipment Under Test (EUT).....	5
SECTION 3: Test Summary	6
SECTION 4: Operation of EUT during testing	9
SECTION 5: Radiated Spurious Emission	11
SECTION 6: Antenna Terminal Conducted Tests	13
APPENDIX 1: Test Data	14
99 % Occupied Bandwidth and 6 dB Bandwidth.....	14
Maximum Peak Output Power	17
Radiated Spurious Emission.....	20
Conducted Spurious Emission.....	31
Power Density	37
APPENDIX 2: Test Instruments	39
APPENDIX 3: Photographs of Test Setup	41
Radiated Spurious Emission.....	41
Worst Case Position	42
Antenna Terminal Conducted Tests	43

SECTION 1: Customer Information

Company Name	Panasonic Corporation of North America
Address	Two Riverfront Plaza, Newark, New Jersey, 07102-5490, USA
Telephone Number	+1-201-348-7760
Contact Person	Ben Botros

***Remarks:**

Panasonic Corporation of North America designates Panasonic Automotive Systems Asia Pacific Co., Ltd as manufacturer of the product (BLE UNIT).

The information provided by the customer is as follows;

- Customer, Description of EUT, Model Number of EUT, FCC ID on the cover and other relevant pages
- Operating/Test Mode(s) (Mode(s)) on all the relevant pages
- SECTION 1: Customer Information
- SECTION 2: Equipment Under Test (EUT) other than the Receipt Date and Test Date
- SECTION 4: Operation of EUT during testing

SECTION 2: Equipment Under Test (EUT)

2.1 Identification of EUT

Description	BLE UNIT
Model Number	HU500030C
Serial Number	Refer to SECTION 4.2
Condition	Engineering prototype (Not for Sale: This sample is equivalent to mass-produced items.)
Modification	No Modification by the test lab
Receipt Date	March 14 and 17, 2025
Test Date	March 24 to September 10, 2025

2.2 Product Description

General Specification

Rating	DC 8 V to 16 V
Operating temperature	-30 deg. C to 80 deg. C

Radio Specification

This report contains data provided by the customer which can impact the validity of results. UL Japan, Inc. is only responsible for the validity of results after the integration of the data provided by the customer. The data provided by the customer is marked "a)" in the table below.

Bluetooth (Low Energy)

Equipment Type	Transceiver
Frequency of Operation	2402 MHz to 2480 MHz
Type of Modulation	GFSK
Antenna Gain ^{a)}	2.9 dBi

SECTION 3: Test Summary

3.1 Test Specification

Test Specification	FCC Part 15 Subpart C The latest version on the first day of the testing period
Title	FCC 47 CFR Part 15 Radio Frequency Device Subpart C Intentional Radiators Section 15.207 Conducted limits Section 15.247 Operation within the bands 902-928 MHz, 2400-2483.5 MHz, and 5725-5850 MHz

3.2 Reference Standards

ANSI/USEMCSC C63.2-2023
ANSI C63.4-2014/C63.4a-2017
ANSI C63.5-2017
ANSI C63.10-2020
ANSI/USEMCSC C63.10/Cor 1-2023
ANSI/USEMCSC C63.10a-2024 for ISED
ANSI C63.25.1-2018
KDB 558074 D01 v05r02
KDB 662911 D01 v02r01 for FCC MIMO device

3.3 Summary of Test Results

Item	Specification	Results	Remarks
Conducted Emission	FCC: Section 15.207 ISED: RSS-Gen 8.8	N/A	*1)
6dB Bandwidth	FCC: Section 15.247(a)(2) ISED: RSS-247 5.2(a)	Complied	Conducted
Maximum Peak Output Power	FCC: Section 15.247(b)(3) ISED: RSS-247 5.4(d)	Complied	Conducted
Power Density	FCC: Section 15.247(e) ISED: RSS-247 5.2(b)	Complied	Conducted
Spurious Emission Restricted Band Edges	FCC: Section 15.247(d) ISED: RSS-247 5.5 RSS-Gen 8.9 RSS-Gen 8.10	Complied	Conducted (below 30 MHz) / Radiated (above 30 MHz) *2)
Note: UL Japan, Inc.'s EMI Work Procedures: Work Instructions-ULID-003591 and Work Instructions-ULID-003593.			
*1) The test is not applicable since the EUT is not the device that is designed to be connected to the public utility (AC) power line.			
*2) Radiated test was selected over 30 MHz based on section 15.247(d) and KDB 558074 D01 15.247 Meas Guidance v05r02 8.5 and 8.6.			

FCC Part 15.31 (e)

This EUT provides the stable voltage constantly to RF part regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203/212 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

3.4 Addition to Standard

Item	Specification	Worst Margin	Results	Remarks
99% Occupied Bandwidth	ISED: -	N/A	-	Conducted

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.5 Uncertainty

Measurement uncertainty is not taken into account when stating conformity with a specified requirement. Note: When margins obtained from test results are less than the measurement uncertainty, the test results may exceed the limit.

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor $k = 2$.

Radiated emission

Measurement distance	Frequency range	Unit	Calculated Uncertainty (+/-)
3 m	9 kHz to 30 MHz	dB	3.3
10 m		dB	3.1
3 m	30 MHz to 200 MHz	Horizontal	5.0
		Vertical	5.0
	200 MHz to 1000 MHz	Horizontal	5.2
		Vertical	6.2
10 m	30 MHz to 200 MHz	Horizontal	5.5
		Vertical	5.4
	200 MHz to 1000 MHz	Horizontal	5.5
		Vertical	5.5
3 m	1 GHz to 6 GHz	dB	5.1
	6 GHz to 18 GHz	dB	5.4
1 m	10 GHz to 18 GHz	dB	5.4
	18 GHz to 26.5 GHz	dB	5.3
	26.5 GHz to 40 GHz	dB	4.8
0.5 m	26.5 GHz to 40 GHz	dB	5.0

Antenna Terminal Conducted

Item	Unit	Calculated Uncertainty (+/-)
Antenna terminated conducted emission / Power density / Burst power	dB	3.50
Adjacent channel power (ACP)	dB	2.32
Bandwidth (OBW)	%	0.96
Time readout (time span upto 100 msec)	%	0.11
Time readout (time span upto 1000 msec)	%	0.11
Time readout (time span upto 60 sec)	%	0.02
Power measurement (Power meter < 8 GHz)	dB	1.43
Power measurement (Call box < 6 GHz)	dB	1.89
Frequency readout (Frequency counter)	ppm	0.67
Frequency readout (Spectrum analyzer frequency readout function)	ppm	2.13
Temperature (constant temperature bath)	deg. C	0.69
Humidity (constant temperature bath)	%RH	2.98
Modulation characteristics	%	6.93
Frequency for mobile	ppm	0.08
Contention-based protocol	dB	2.97

3.6 Test Location

UL Japan, Inc. Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 Japan

Telephone: +81-596-24-8999

A2LA Certificate Number: 5107.02 / FCC Test Firm Registration Number: 884919

ISED Lab Company Number: 2973C / CAB identifier: JP0002

Test site	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms	Maximum measurement distance
No.1 semi-anechoic chamber	19.2 x 11.2 x 7.7	7.0 x 6.0	No.1 Power source room	10 m
No.2 semi-anechoic chamber	7.5 x 5.8 x 5.2	4.0 x 4.0	-	3 m
No.3 semi-anechoic chamber	12.0 x 8.5 x 5.9	6.8 x 5.75	No.3 Preparation room	3 m
No.3 shielded room	4.0 x 6.0 x 2.7	N/A	-	-
No.4 semi-anechoic chamber	12.0 x 8.5 x 5.9	6.8 x 5.75	No.4 Preparation room	3 m
No.4 shielded room	4.0 x 6.0 x 2.7	N/A	-	-
No.5 semi-anechoic chamber	6.0 x 6.0 x 3.9	6.0 x 6.0	-	-
No.5 measurement room	6.4 x 6.4 x 3.0	6.4 x 6.4	-	-
No.6 shielded room	4.0 x 4.5 x 2.7	4.0 x 4.5	-	-
No.6 measurement room	4.75 x 5.4 x 3.0	4.75 x 4.15	-	-
No.7 shielded room	4.7 x 7.5 x 2.7	4.7 x 7.5	-	-
No.8 measurement room	3.1 x 5.0 x 2.7	3.1 x 5.0	-	-
No.9 measurement room	8.8 x 4.6 x 2.8	2.4 x 2.4	-	-
No.10 shielded room	3.8 x 2.8 x 2.8	3.8 x 2.8	-	-
No.11 measurement room	4.0 x 3.4 x 2.5	N/A	-	-
No.12 measurement room	2.6 x 3.4 x 2.5	N/A	-	-
Large Chamber	16.9 x 22.1 x 10.17	16.9 x 22.1	-	10 m
Small Chamber	5.3 x 6.69 x 3.59	5.3 x 6.69	-	-

3.7 Test Data, Test Instruments, and Test Set Up

Refer to APPENDIX.

SECTION 4: Operation of EUT during testing

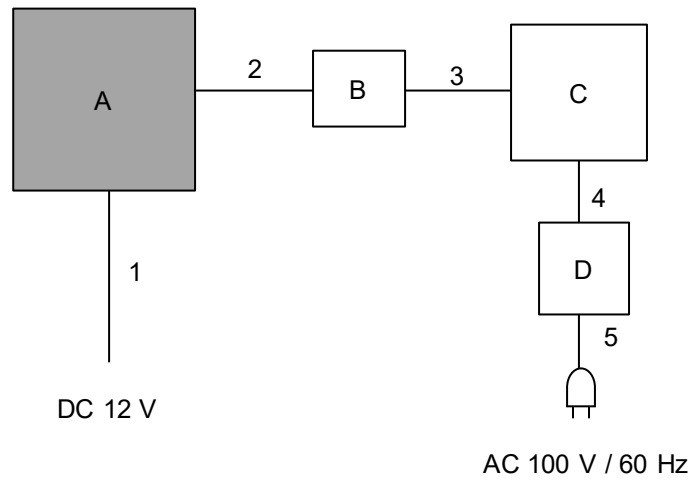
4.1 Operating Mode(s)

Mode	Remarks*
Bluetooth Low Energy (BT LE)	Uncoded 1M-PHY, Maximum Packet Size, PRBS9
	Uncoded 2M-PHY, Maximum Packet Size, PRBS9
<p>*Power of the EUT was set by the software as follows; Power Setting: 5 dBm Software: kw45_connectivity_test, Version: 2.12.7 (Date: March 24, 2025, Storage location: EUT memory)</p> <p>*This setting of software is the worst case. Any conditions under the normal use do not exceed the condition of setting. In addition, end users cannot change the settings of the output power of the product.</p>	

*The Details of Operating Mode(s)

Test Item	Operating Mode	Tested Frequency
Radiated Spurious Emission (Below 1 GHz)	Tx BT LE 1M-PHY *1)	2402 MHz
Radiated Spurious Emission (Above 1 GHz), Maximum Peak Output Power, Power Density, 6dB Bandwidth, 99% Occupied Bandwidth, Conducted Spurious Emission	Tx BT LE 1M-PHY Tx BT LE 2M-PHY	2402 MHz 2442 MHz 2480 MHz
<p>*1) Spurious emissions for frequencies below 1 GHz were limited to the channel that had the highest power during the antenna terminal test, as preliminary testing indicated that changing the operating frequency had no significant impact on the emissions in those frequency bands.</p>		

4.2 Configuration and Peripherals



* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support Equipment

No.	Item	Model number	Serial Number	Manufacturer	Remarks
A	BLE UNIT	HU500030C	No.214 for RE* No.215 for AT*	Panasonic Automotive Systems Asia Pacific Co., Ltd	EUT
B	USB-Serial-FTDI	-	-	Mikroelektronika	-
C	Laptop PC	CF-N8HWCDPS	0BKSA07449	Panasonic	-
D	AC Adapter	CF-AA6372B	6372BM409X17298B	Panasonic	-

List of Cables Used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	DC Cable	2.0	Unshielded	Unshielded	-
2	Signal Cable	0.2	Unshielded	Unshielded	-
3	USB Cable	1.0	Shielded	Shielded	-
4	DC Cable	1.0	Unshielded	Unshielded	-
5	AC Cable	1.8	Unshielded	Unshielded	-

*RE: Radiated Spurious Emission
AT: Antenna Terminal Conducted Tests

SECTION 5: Radiated Spurious Emission

Test Procedure

[For below 1 GHz]

EUT was placed on a urethane platform of nominal size, 0.5 m by 1.0 m, raised 0.8 m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

[For above 1 GHz]

EUT was placed on a urethane platform of nominal size, 0.5 m by 0.5 m, raised 1.5 m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with absorbent materials lined on a ground plane. Test antenna was aimed at the EUT for receiving the maximum signal and always kept within the illumination area of the 3 dB beamwidth of the antenna.

The height of the measuring antenna varied between 1 m and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	30 MHz to 200 MHz	200 MHz to 1 GHz	Above 1 GHz
Antenna Type	Biconical	Logperiodic	Horn

In any 100 kHz bandwidth outside the restricted band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

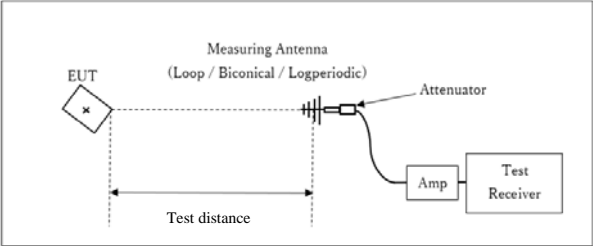
20 dBc was applied to the frequency over the limit of FCC 15.209 / Table 4 of RSS-Gen 8.9(ISED) and outside the restricted band of FCC15.205 / Table 6 of RSS-Gen 8.10 (ISED).

It was measured with the settings below based on ANSI C63.10.

Frequency	Below 1 GHz	Above 1 GHz		20 dBc
Instrument Used	Test Receiver	Spectrum Analyzer		Spectrum Analyzer
Detector	QP	PK	AV	PK
IF Bandwidth	BW 120 kHz	RBW: 1 MHz VBW: 3 MHz	11.12.2.5.1 RBW: 1 MHz VBW: 3 MHz Detector: Power Averaging (RMS) Trace: 100 traces	RBW: 100 kHz VBW: 300 kHz

Figure 1: Test Setup

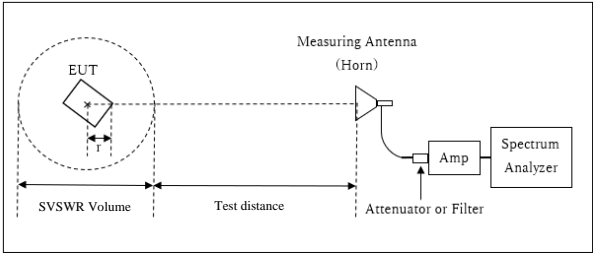
Below 1 GHz



* : Center of turn table

Test Distance: 3 m

1 GHz to 10 GHz



r : Radius of an outer periphery of EUT
 * : Center of turn table

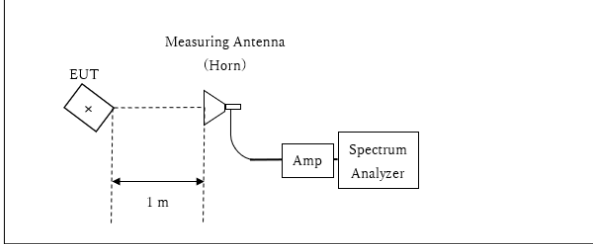
[1 GHz to 10 GHz]

Distance Factor: $20 \times \log (3.75 \text{ m}^* / 3.0 \text{ m}) = 1.94 \text{ dB}$
 *(Test Distance + SVSWR Volume / 2) - r = 3.75 m

Test Distance: 3 m
 SVSWR Volume: 1.5m
 (SVSWR Volume has been calibrated based on CISPR 16-1-4.)
 r: 0.0m

(The test was performed with r = 0.0 m since EUT is small and it was the rather conservative condition.)

10 GHz to 26.5 GHz



* : Center of turn table

Distance Factor: $20 \times \log (1.0 \text{ m} / 3.0 \text{ m}) = -9.5 \text{ dB}$
 *Test Distance: 1 m

The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

Test results are rounded off and limit are rounded down, so some differences might be observed.

Measurement Range : 30 MHz to 26.5 GHz
 Test Data : APPENDIX
 Test Result : Pass

SECTION 6: Antenna Terminal Conducted Tests

Test Procedure

The tests were made with below setting connected to the antenna port.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument Used
6dB Bandwidth	3 MHz	100 kHz	300 kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth *1)	Enough width to display emission skirts	1 to 5 % of OBW	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Auto	Peak	-	Power Meter (Sensor: 50 MHz BW)
Peak Power Density	1.5 times the 6dB Bandwidth	3 kHz	10 kHz	Auto	Peak	Max Hold	Spectrum Analyzer *2)
Conducted Spurious Emission *3) *4)	9 kHz to 150 kHz	200 Hz	620 Hz	Auto	Peak	Max Hold	Spectrum Analyzer
	150 kHz to 30 MHz	10 kHz	30 kHz				

*1) Peak hold was applied as Worst-case measurement.

*2) Section 11.10.2 Method PKPSD (peak PSD) of "ANSI C63.10-2020".

*3) In the frequency range below 30MHz, RBW was narrowed to separate the noise contents.

Then, wide-band noise near the limit was checked separately, however the noise was not detected as shown in the chart.

(9 kHz - 150 kHz: RBW = 200 Hz, 150 kHz - 30 MHz: RBW = 10 kHz)

*4) The limits in CFR 47, Part 15, Subpart C, paragraph 15.209(a), are identical to those in RSS-Gen section 8.9, Table 6, since the measurements are performed in terms of magnetic field strength and converted to electric field strength levels (as reported in the table) using the free space impedance of 377 Ohms. For example, the measurement at frequency 9 kHz resulted in a level of 45.5 dBuV/m, which is equivalent to $45.5 - 51.5 = -6.0$ dBuA/m, which has the same margin, 3 dB, to the corresponding RSS-Gen Table 6 limit as it has to 15.209(a) limit.

Test results are rounded off and limit are rounded down, so some differences might be observed.
The equipment and cables were not used for factor 0 dB of the data sheets.

Test Data : APPENDIX
Test Result : Pass

APPENDIX 1: Test Data

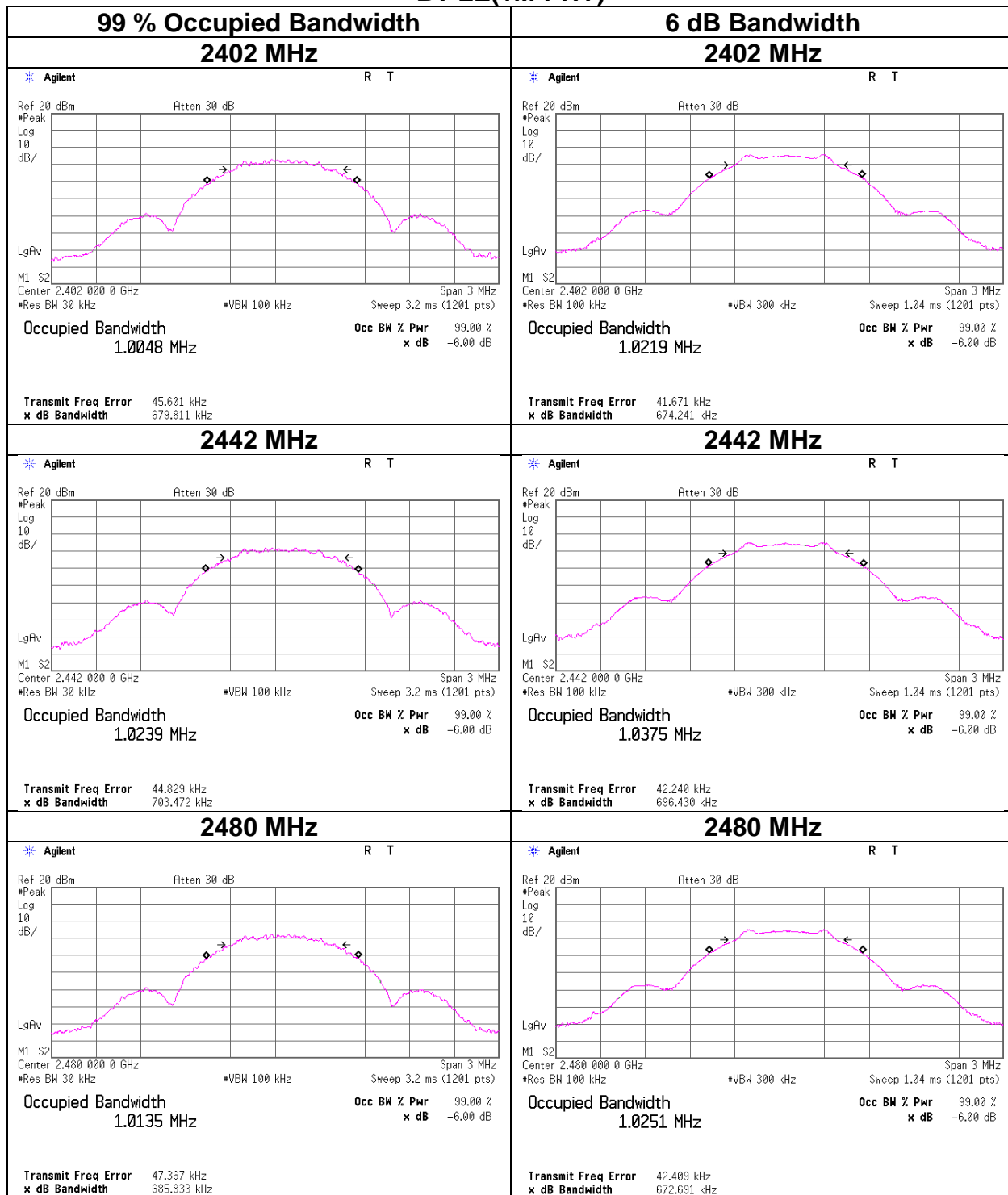
99 % Occupied Bandwidth and 6 dB Bandwidth

Test place Ise EMC Lab. No.8 Measurement Room
Date March 24, 2025
Temperature / Humidity 25 deg. C / 46 % RH
Engineer Takeshi Hiyaji
Mode Tx BT LE

Mode	Frequency [MHz]	99% Occupied Bandwidth [kHz]	6dB Bandwidth [MHz]	Limit for 6dB Bandwidth [MHz]
BT LE(1M-PHY)	2402	1004.8	0.674	> 0.5000
	2442	1023.9	0.696	> 0.5000
	2480	1013.5	0.673	> 0.5000
BT LE(2M-PHY)	2402	2043.4	1.381	> 0.5000
	2442	2037.7	1.388	> 0.5000
	2480	2040.7	1.409	> 0.5000

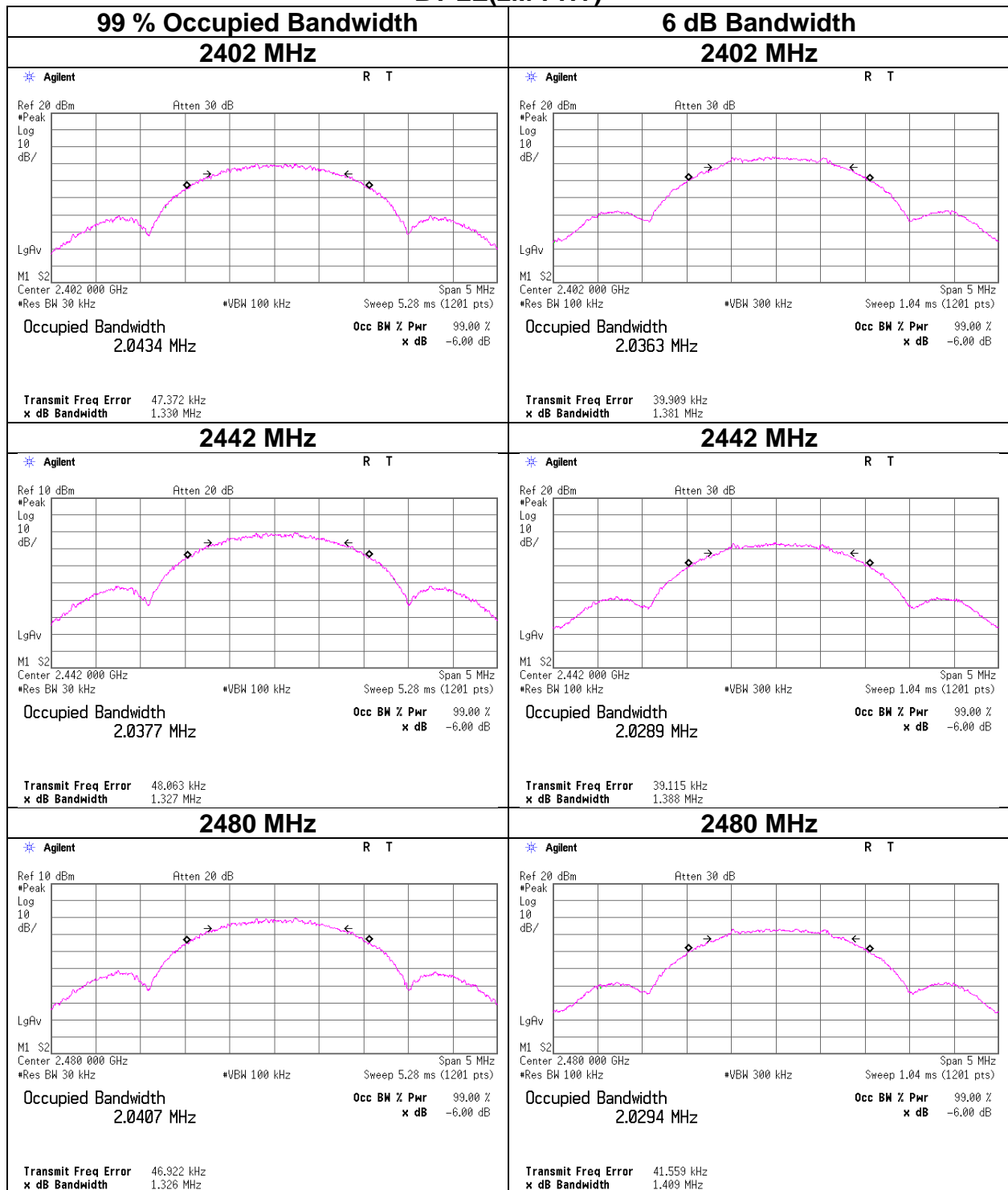
99 % Occupied Bandwidth and 6 dB Bandwidth

BT LE(1M-PHY)



99 % Occupied Bandwidth and 6 dB Bandwidth

BT LE(2M-PHY)



Maximum Peak Output Power

Test place	Ise EMC Lab. No.8 Measurement Room
Date	September 10, 2025
Temperature / Humidity	22 deg. C / 42 % RH
Engineer	Tetsuro Yoshida
Mode	Tx BT LE 1M-PHY

Freq.	Reading	Cable Loss	Atten. Loss	Conducted Power					e.i.r.p. for RSS-247					
				Result		Limit		Margin	Antenna Gain	Result		Limit		Margin
				[dBm]	[mW]	[dBm]	[mW]			[dB]	[dBm]	[mW]	[dBm]	
[MHz]	[dBm]	[dB]	[dB]	[dBm]	[mW]	[dBm]	[mW]	[dB]	[dB]	[dBm]	[mW]	[dBm]	[mW]	[dB]
2402	-3.46	0.55	9.73	6.82	4.81	30.00	1000	23.18	2.90	9.72	9.38	36.02	4000	26.30
2442	-3.70	0.55	9.73	6.58	4.55	30.00	1000	23.42	2.90	9.48	8.87	36.02	4000	26.54
2480	-3.73	0.56	9.73	6.56	4.53	30.00	1000	23.44	2.90	9.46	8.83	36.02	4000	26.56

Sample Calculation:

Result = Reading + Cable Loss (including the cable(s) customer supplied) + Attenuator Loss

e.i.r.p. Result = Conducted Power Result + Antenna Gain

Maximum Peak Output Power

Test place Ise EMC Lab. No.8 Measurement Room
Date September 10, 2025
Temperature / Humidity 22 deg. C / 42 % RH
Engineer Tetsuro Yoshida
Mode Tx BT LE 2M-PHY

Freq.	Reading	Cable Loss	Atten. Loss	Conducted Power					e.i.r.p. for RSS-247					
				Result		Limit		Margin	Antenna Gain	Result		Limit		Margin
				[dBm]	[mW]	[dBm]	[mW]			[dB]	[dBm]	[mW]	[dBm]	
2402	-3.48	0.55	9.73	6.80	4.79	30.00	1000	23.20	2.90	9.70	9.33	36.02	4000	26.32
2442	-3.73	0.55	9.73	6.55	4.52	30.00	1000	23.45	2.90	9.45	8.81	36.02	4000	26.57
2480	-3.81	0.56	9.73	6.48	4.45	30.00	1000	23.52	2.90	9.38	8.67	36.02	4000	26.64

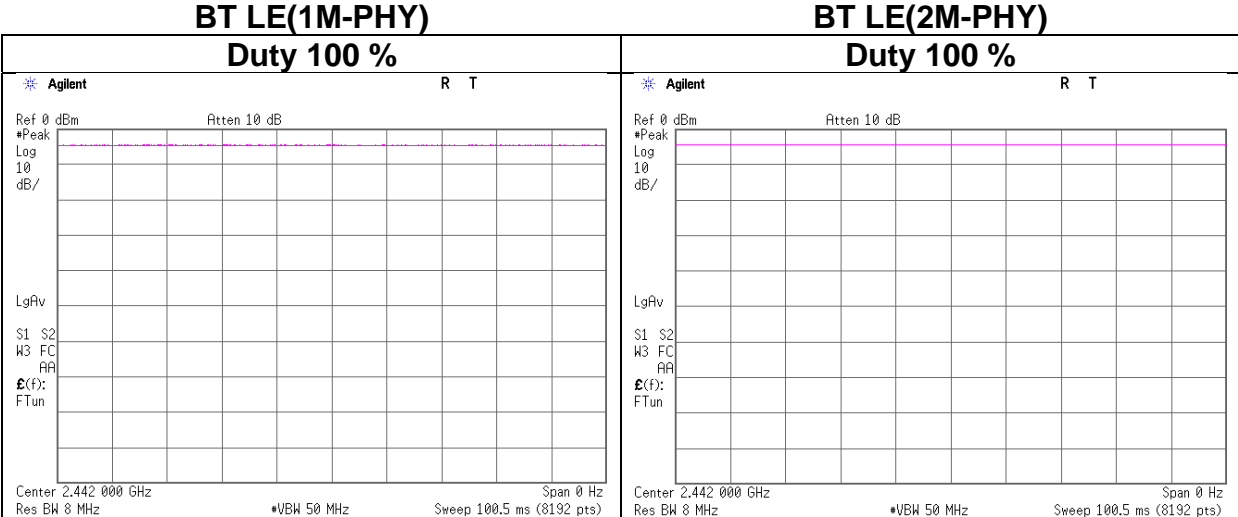
Sample Calculation:

Result = Reading + Cable Loss (including the cable(s) customer supplied) + Attenuator Loss

e.i.r.p. Result = Conducted Power Result + Antenna Gain

Burst rate confirmation

Test place Ise EMC Lab. No.8 Measurement Room
 Date March 24, 2025
 Temperature / Humidity 25 deg. C / 46 % RH
 Engineer Takeshi Hiyaji
 Mode Tx BT LE



* Since the burst rate is not different between the channels, the data has been obtained on the representative channel.

Radiated Spurious Emission

Test place	Ise EMC Lab.	
Semi Anechoic Chamber	No.2	No.2
Date	March 26, 2025	March 27, 2025
Temperature / Humidity	20 deg. C / 50 % RH	20 deg. C / 42 % RH
Engineer	Tetsuro Yoshida	Shousei Hamaguchi
	(1 GHz to 26.5 GHz)	(Below 1 GHz)
Mode	Tx BT LE 1M-PHY 2402 MHz	

Polarity	Frequency	Reading (QP / PK)	Reading (AV)	Ant. Factor	Loss	Gain	Duty Factor	Result (QP / PK)	Result (AV)	Limit (QP / PK)	Limit (AV)	Margin (QP / PK)	Margin (AV)	Remark
[Hori/Vert]	[MHz]	[dBuV]	[dBuV]	[dB/m]	[dB]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dBuV/m]	[dBuV/m]	[dB]	[dB]	
Hori.	57.1	22.8	-	8.6	7.2	28.5	-	10.0	-	40.0	-	30.0	-	Floor noise
Hori.	123.8	21.7	-	13.2	7.7	28.3	-	14.3	-	43.5	-	29.2	-	Floor noise
Hori.	150.0	21.8	-	15.0	7.9	28.3	-	16.5	-	43.5	-	27.1	-	Floor noise
Hori.	232.6	21.1	-	11.6	8.5	27.9	-	13.3	-	46.0	-	32.7	-	Floor noise
Hori.	282.5	21.0	-	13.5	8.8	27.8	-	15.6	-	46.0	-	30.5	-	Floor noise
Hori.	393.4	21.4	-	15.6	9.4	28.4	-	18.0	-	46.0	-	28.0	-	Floor noise
Hori.	2390.0	44.9	35.8	27.5	5.0	33.2	-	44.2	35.1	73.9	53.9	29.7	18.8	
Hori.	4804.0	45.2	38.1	31.4	7.2	32.6	-	51.2	44.1	73.9	53.9	22.7	9.8	
Hori.	7206.0	46.8	38.7	35.3	8.4	32.5	-	58.1	50.0	73.9	53.9	15.8	3.9	
Hori.	9608.0	44.4	34.7	35.8	9.1	33.2	-	56.2	46.4	73.9	53.9	17.7	7.5	Floor noise
Hori.	12010.0	44.7	36.9	38.5	-1.6	32.4	-	49.2	41.4	73.9	53.9	24.7	12.5	
Vert.	57.1	22.8	-	8.6	7.2	28.5	-	10.0	-	40.0	-	30.0	-	Floor noise
Vert.	123.8	21.7	-	13.2	7.7	28.3	-	14.3	-	43.5	-	29.2	-	Floor noise
Vert.	150.0	21.8	-	15.0	7.9	28.3	-	16.5	-	43.5	-	27.1	-	Floor noise
Vert.	232.6	21.1	-	11.6	8.5	27.9	-	13.3	-	46.0	-	32.7	-	Floor noise
Vert.	282.5	21.0	-	13.5	8.8	27.8	-	15.6	-	46.0	-	30.5	-	Floor noise
Vert.	393.4	21.4	-	15.6	9.4	28.4	-	18.0	-	46.0	-	28.0	-	Floor noise
Vert.	2390.0	44.3	35.9	27.5	5.0	33.2	-	43.6	35.2	73.9	53.9	30.3	18.7	
Vert.	4804.0	44.6	36.9	31.4	7.2	32.6	-	50.6	42.9	73.9	53.9	23.3	11.0	
Vert.	7206.0	46.7	38.7	35.3	8.4	32.5	-	57.9	49.9	73.9	53.9	16.0	4.0	
Vert.	9608.0	44.5	34.5	35.8	9.1	33.2	-	56.3	46.3	73.9	53.9	17.6	7.6	Floor noise
Vert.	12010.0	44.5	36.9	38.5	-1.6	32.4	-	49.1	41.4	73.9	53.9	24.8	12.5	

Result (QP / PK) = Reading + Ant Factor + Loss (Cable+Attenuator+Filter+Distance factor(above 1 GHz)) - Gain(Amplifier)
 Result (AV)= Reading + Ant Factor + Loss (Cable+Attenuator+Filter+Distance factor(above 1 GHz)) - Gain(Amplifier) + Duty factor
 *Other frequency noises omitted in this report were not seen or had enough margin (more than 20 dB).
 *QP detector was used up to 1GHz.

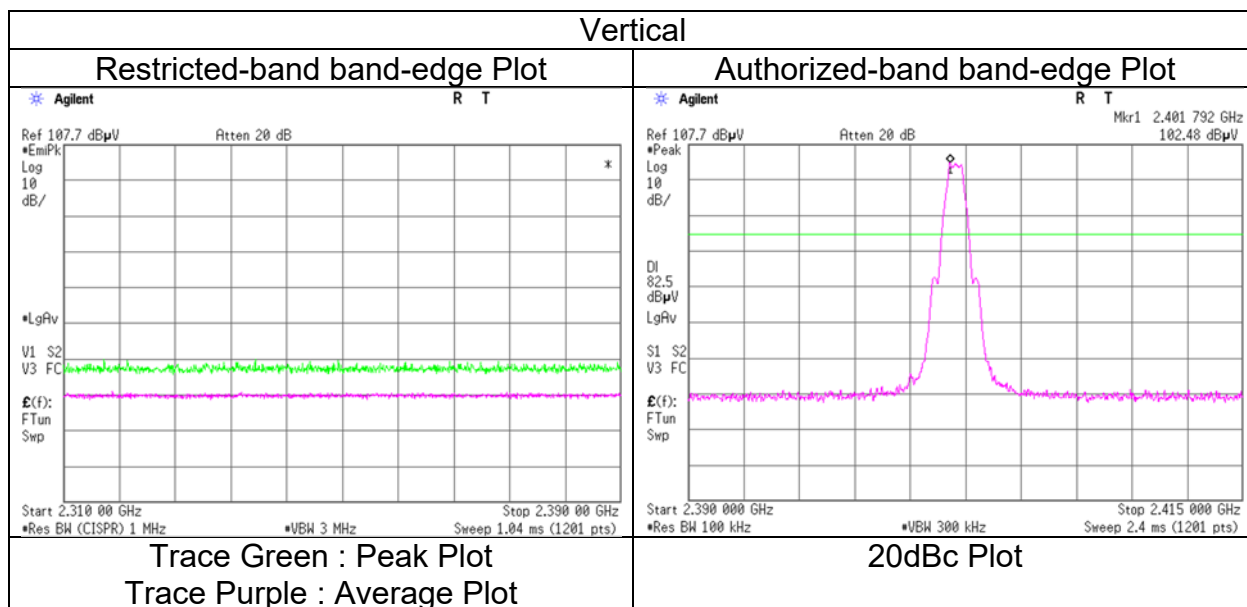
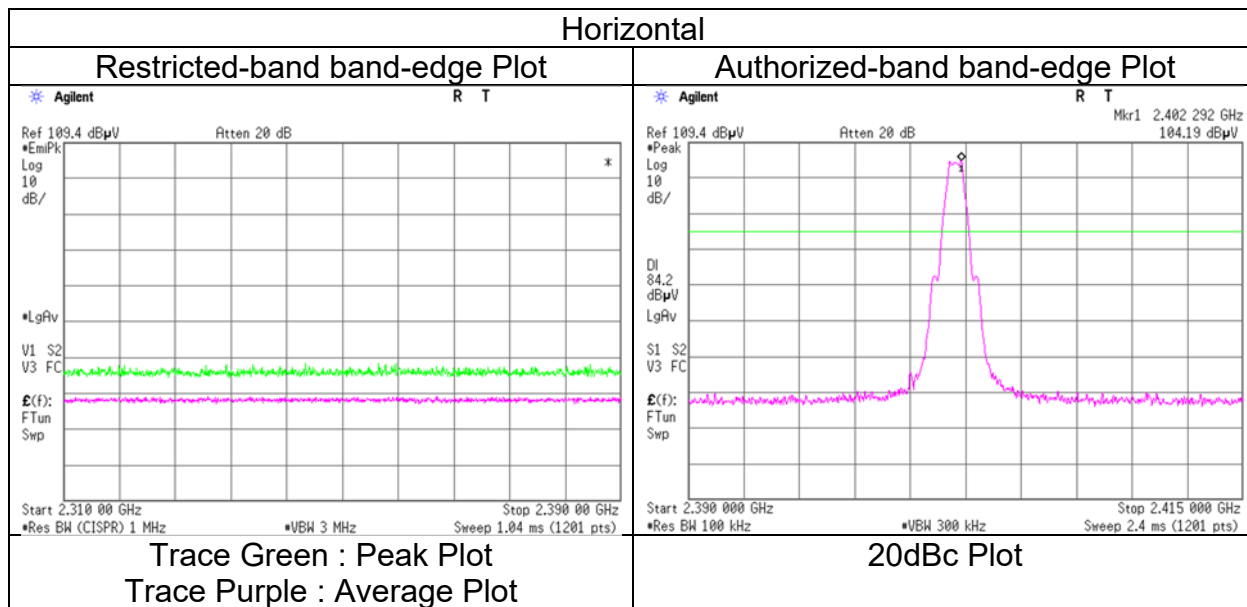
20dBc Data Sheet

Polarity	Frequency	Reading (PK)	Ant Factor	Loss	Gain	Result	Limit	Margin	Remark
[Hori/Vert]	[MHz]	[dBuV]	[dB/m]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	
Hori.	2402.0	104.2	27.5	5.0	33.2	103.5	-	-	Carrier
Hori.	2400.0	44.6	27.5	5.0	33.2	43.9	83.5	39.6	
Vert.	2402.0	102.5	27.5	5.0	33.2	101.8	-	-	Carrier
Vert.	2400.0	43.0	27.5	5.0	33.2	42.3	81.8	39.4	

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter+Distance factor(above 1 GHz)) - Gain(Amplifier)
 Distance factor:
 1 GHz - 6 GHz 20log (3.75 m / 3.0 m) = 1.94 dB
 6 GHz - 10 GHz 20log (3.75 m / 3.0 m) = 1.94 dB
 10 GHz - 26.5 GHz 20log (1.0 m / 3.0 m) = -9.5 dB

Radiated Spurious Emission (Reference Plot for band-edge)

Test place	Ise EMC Lab.
Semi Anechoic Chamber	No.2
Date	March 26, 2025
Temperature / Humidity	20 deg. C / 50 % RH
Engineer	Tetsuro Yoshida
	(1 GHz to 26.5 GHz)
Mode	Tx BT LE 1M-PHY 2402 MHz

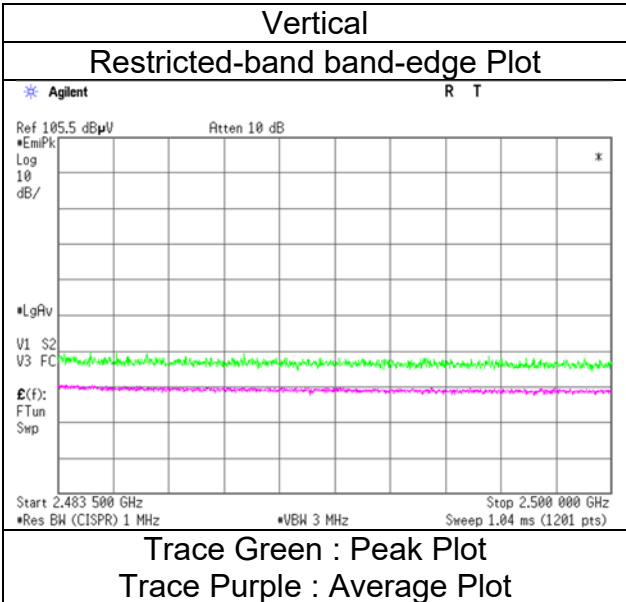
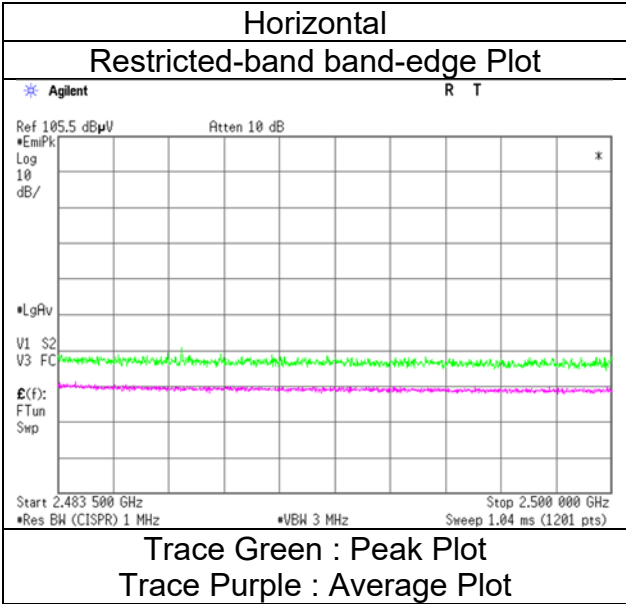


* The measurement was conducted for a sufficiently long enough time to detect any possible spurious emissions.
Final result of restricted band edge and authorized band edge were shown in tabular data.

**Radiated Spurious Emission
 (Reference Plot for band-edge)**

Test place
 Semi Anechoic Chamber
 Date
 Temperature / Humidity
 Engineer
 Mode

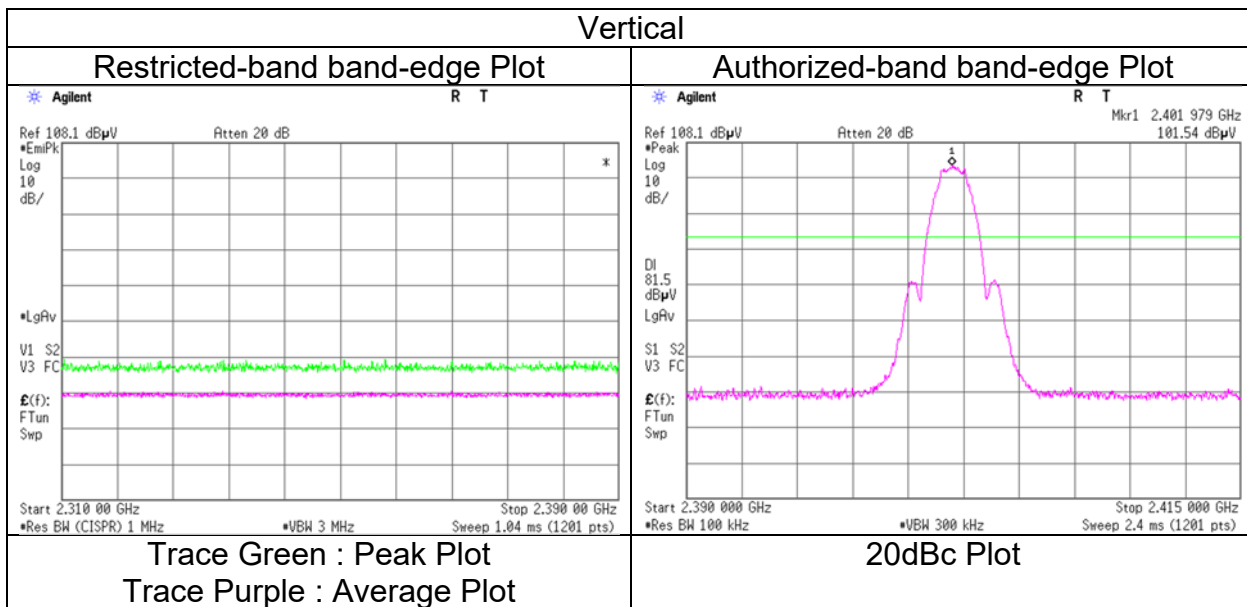
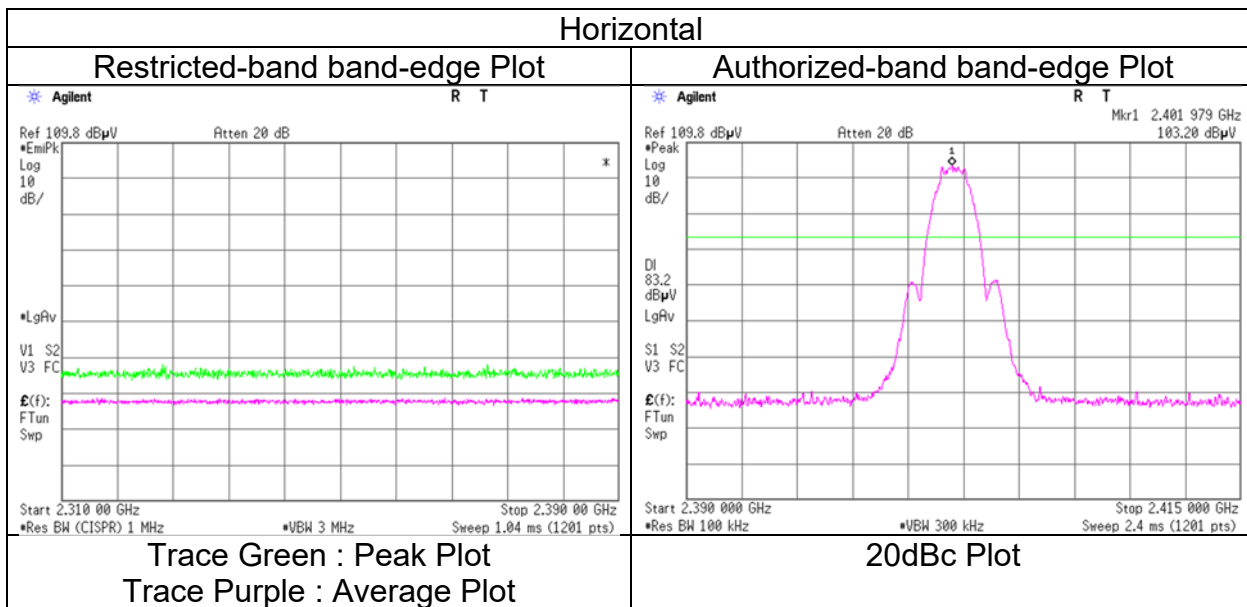
Ise EMC Lab.
 No.2
 March 26, 2025
 20 deg. C / 50 % RH
 Tetsuro Yoshida
 (1 GHz to 26.5 GHz)
 Tx BT LE 1M-PHY 2480 MHz



* The measurement was conducted for a sufficiently long enough time to detect any possible spurious emissions.
 Final result of restricted band edge was shown in tabular data.

Radiated Spurious Emission (Reference Plot for band-edge)

Test place	Ise EMC Lab.
Semi Anechoic Chamber	No.2
Date	March 26, 2025
Temperature / Humidity	20 deg. C / 50 % RH
Engineer	Tetsuro Yoshida
	(1 GHz to 26.5 GHz)
Mode	Tx BT LE 2M-PHY 2402 MHz

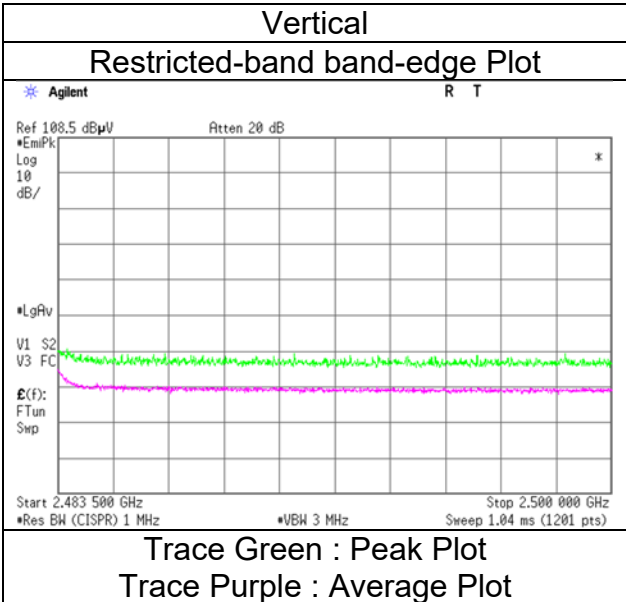
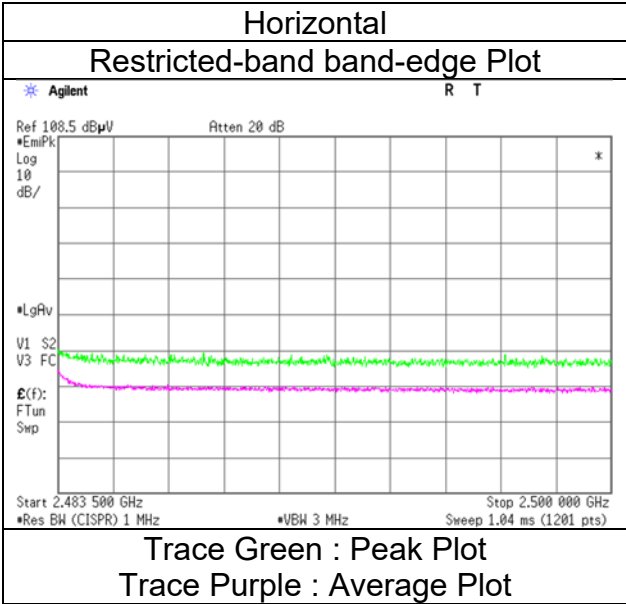


* The measurement was conducted for a sufficiently long enough time to detect any possible spurious emissions.
Final result of restricted band edge and authorized band edge were shown in tabular data.

**Radiated Spurious Emission
 (Reference Plot for band-edge)**

Test place
 Semi Anechoic Chamber
 Date
 Temperature / Humidity
 Engineer
 Mode

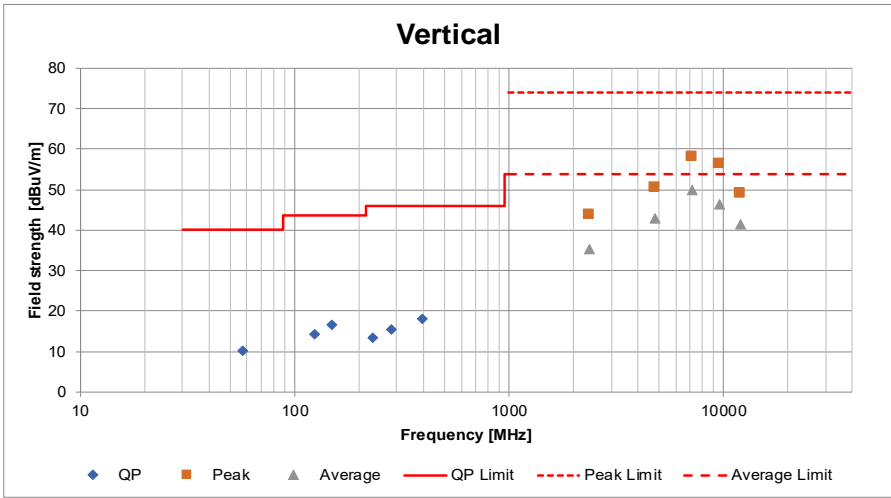
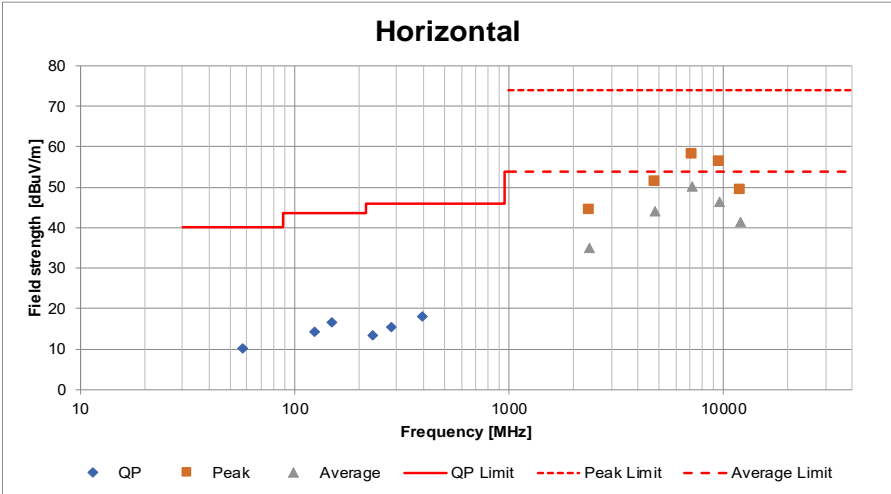
Ise EMC Lab.
 No.2
 March 26, 2025
 20 deg. C / 50 % RH
 Tetsuro Yoshida
 (1 GHz to 26.5 GHz)
 Tx BT LE 2M-PHY 2480 MHz



* The measurement was conducted for a sufficiently long enough time to detect any possible spurious emissions.
 Final result of restricted band edge was shown in tabular data.

Radiated Spurious Emission
(Plot data, Worst case mode for Maximum Peak Output Power)

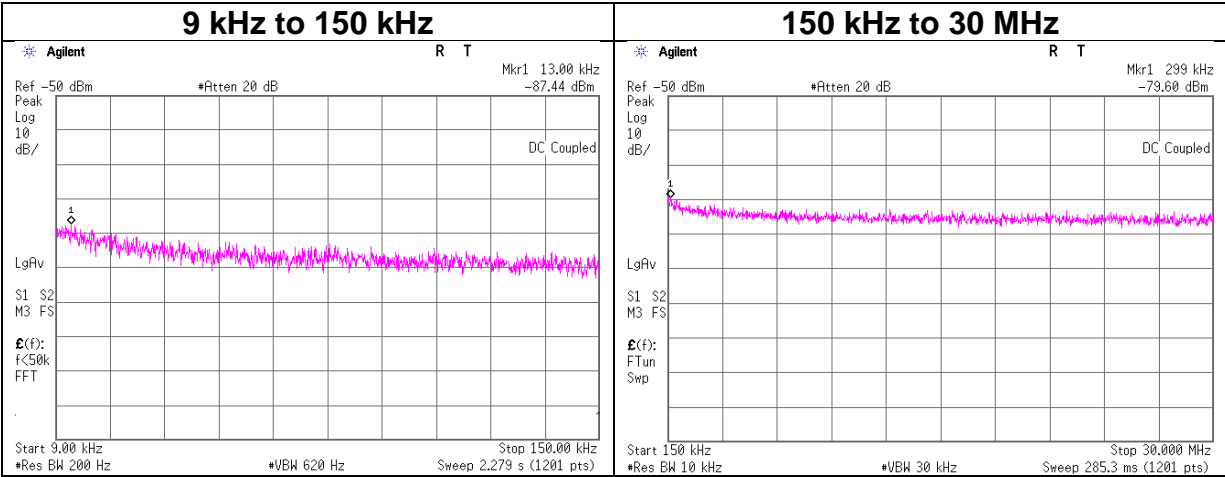
Test place	Ise EMC Lab.	
Semi Anechoic Chamber	No.2	No.2
Date	March 26, 2025	March 27, 2025
Temperature / Humidity	20 deg. C / 50 % RH	20 deg. C / 42 % RH
Engineer	Tetsuro Yoshida	Shousei Hamaguchi
	(1 GHz to 26.5 GHz)	(Below 1 GHz)
Mode	Tx BT LE 1M-PHY 2402 MHz	



*These plots data contain sufficient number to show the trend of characteristic features for EUT.

Conducted Spurious Emission

Test place Ise EMC Lab. No.8 Measurement Room
 Date March 24, 2025
 Temperature / Humidity 25 deg. C / 46 % RH
 Engineer Takeshi Hiyaji
 Mode Tx BT LE (1M-PHY) 2402 MHz

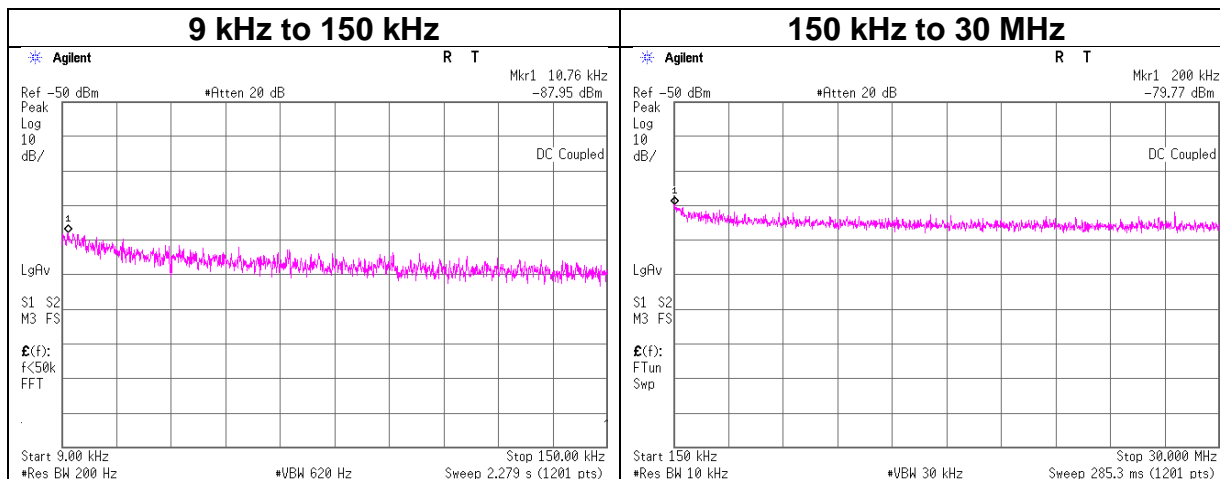


Frequency [kHz]	Reading [dBm]	Cable Loss [dB]	Attenuator Loss [dB]	Antenna Gain [dBi]	N (Number of Output)	EIRP [dBm]	Distance [m]	Ground bounce [dB]	E (field strength) [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
13.00	-87.4	0.10	9.8	2.9	1	-74.6	300	6.0	-13.4	45.3	58.7	
299.00	-79.6	0.10	9.8	2.9	1	-66.8	300	6.0	-5.5	18.0	23.5	

$E [dBuV/m] = EIRP [dBm] - 20 \log (Distance [m]) + Ground\ bounce [dB] + 104.8 [dBuV/m]$
 $EIRP[dBm] = Reading [dBm] + Cable\ loss [dB] + Attenuator\ Loss [dB] + Antenna\ gain [dBi] + 10 * \log (N)$
 N: Number of output

Conducted Spurious Emission

Test place	Ise EMC Lab. No.8 Measurement Room
Date	March 24, 2025
Temperature / Humidity	25 deg. C / 46 % RH
Engineer	Takeshi Hiyaji
Mode	Tx BT LE (1M-PHY) 2442 MHz



Frequency [kHz]	Reading [dBm]	Cable Loss [dB]	Attenuator Loss [dB]	Antenna Gain [dBi]	N (Number of Output)	EIRP [dBm]	Distance [m]	Ground bounce [dB]	E (field strength) [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
10.76	-88.0	0.10	9.8	2.9	1	-75.1	300	6.0	-13.9	46.9	60.8	
200.00	-79.8	0.10	9.8	2.9	1	-66.9	300	6.0	-5.7	21.5	27.2	

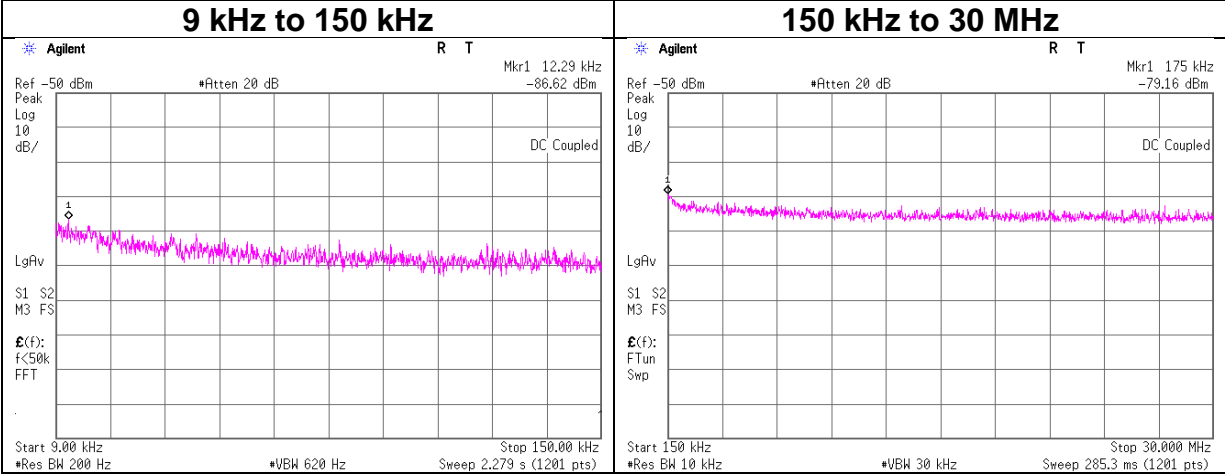
$E \text{ [dBuV/m]} = \text{EIRP [dBm]} - 20 \log(\text{Distance [m]}) + \text{Ground bounce [dB]} + 104.8 \text{ [dBuV/m]}$

$\text{EIRP [dBm]} = \text{Reading [dBm]} + \text{Cable loss [dB]} + \text{Attenuator Loss [dB]} + \text{Antenna gain [dBi]} + 10 * \log(N)$

N: Number of output

Conducted Spurious Emission

Test place Ise EMC Lab. No.8 Measurement Room
 Date March 24, 2025
 Temperature / Humidity 25 deg. C / 46 % RH
 Engineer Takeshi Hiyaji
 Mode Tx BT LE (1M-PHY) 2480 MHz

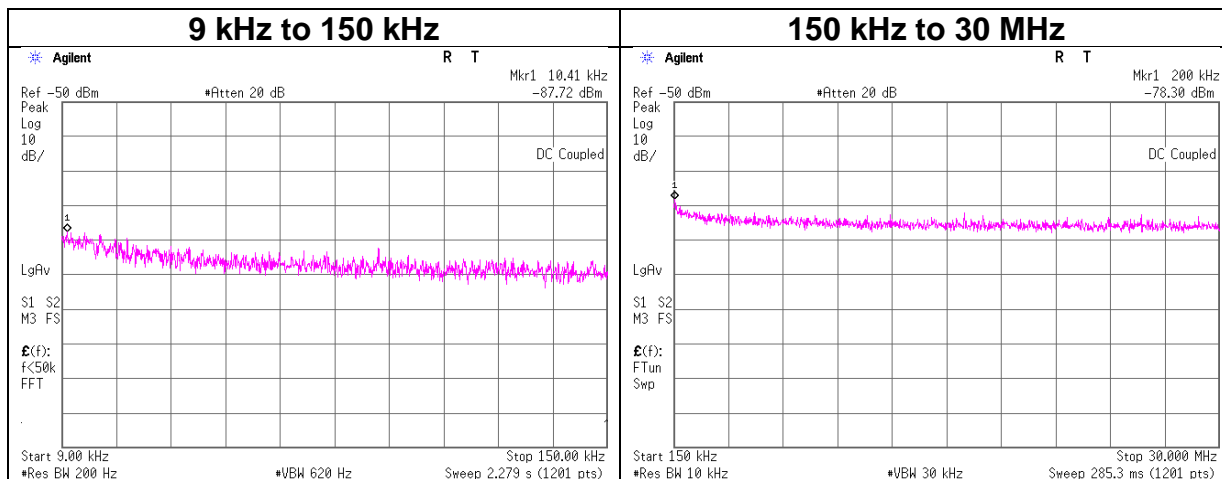


Frequency [kHz]	Reading [dBm]	Cable Loss [dB]	Attenuator Loss [dB]	Antenna Gain [dBi]	N (Number of Output)	EIRP [dBm]	Distance [m]	Ground bounce [dB]	E (field strength) [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
12.29	-86.6	0.10	9.8	2.9	1	-73.8	300	6.0	-12.5	45.8	58.3	
175.00	-79.2	0.10	9.8	2.9	1	-66.3	300	6.0	-5.1	22.7	27.8	

$E [dBuV/m] = EIRP [dBm] - 20 \log (Distance [m]) + Ground\ bounce [dB] + 104.8 [dBuV/m]$
 $EIRP [dBm] = Reading [dBm] + Cable\ loss [dB] + Attenuator\ Loss [dB] + Antenna\ gain [dBi] + 10 * \log (N)$
 N: Number of output

Conducted Spurious Emission

Test place	Ise EMC Lab. No.8 Measurement Room
Date	March 24, 2025
Temperature / Humidity	25 deg. C / 46 % RH
Engineer	Takeshi Hiyaji
Mode	Tx BT LE (2M-PHY) 2402 MHz



Frequency [kHz]	Reading [dBm]	Cable Loss [dB]	Attenuator Loss [dB]	Antenna Gain [dBi]	N (Number of Output)	EIRP [dBm]	Distance [m]	Ground bounce [dB]	E (field strength) [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
10.41	-87.7	0.10	9.8	2.9	1	-74.9	300	6.0	-13.6	47.2	60.8	
200.00	-78.3	0.10	9.8	2.9	1	-65.5	300	6.0	-4.2	21.5	25.7	

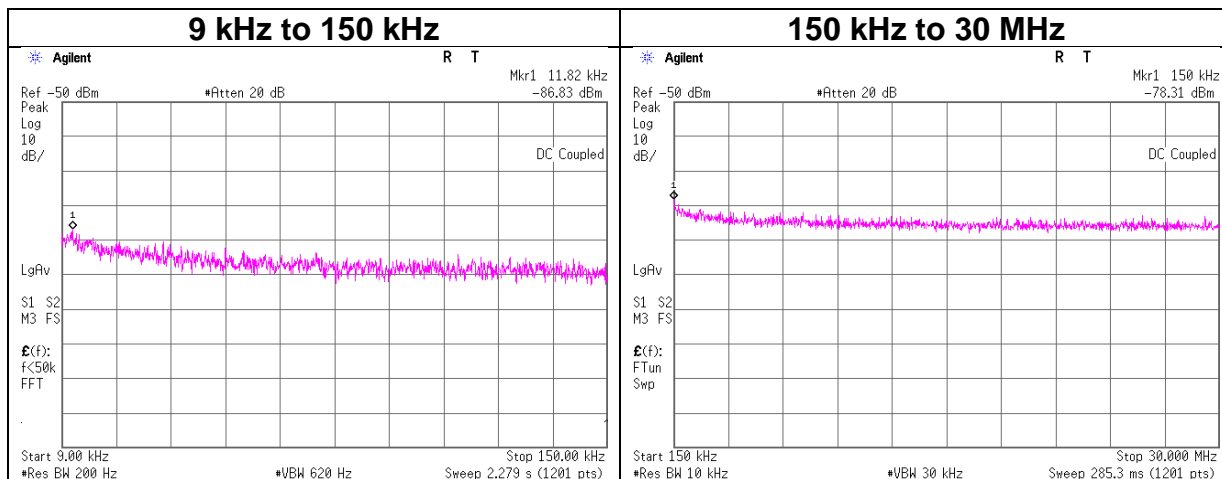
$$E \text{ [dBuV/m]} = \text{EIRP [dBm]} - 20 \log(\text{Distance [m]}) + \text{Ground bounce [dB]} + 104.8 \text{ [dBuV/m]}$$

$$\text{EIRP [dBm]} = \text{Reading [dBm]} + \text{Cable loss [dB]} + \text{Attenuator Loss [dB]} + \text{Antenna gain [dBi]} + 10 * \log(N)$$

N: Number of output

Conducted Spurious Emission

Test place Ise EMC Lab. No.8 Measurement Room
 Date March 24, 2025
 Temperature / Humidity 25 deg. C / 46 % RH
 Engineer Takeshi Hiyaji
 Mode Tx BT LE (2M-PHY) 2442 MHz



Frequency [kHz]	Reading [dBm]	Cable Loss [dB]	Attenuator Loss [dB]	Antenna Gain [dBi]	N (Number of Output)	EIRP [dBm]	Distance [m]	Ground bounce [dB]	E (field strength) [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
11.82	-86.8	0.10	9.8	2.9	1	-74.0	300	6.0	-12.7	46.1	58.8	
150.00	-78.3	0.10	9.8	2.9	1	-65.5	300	6.0	-4.2	24.0	28.2	

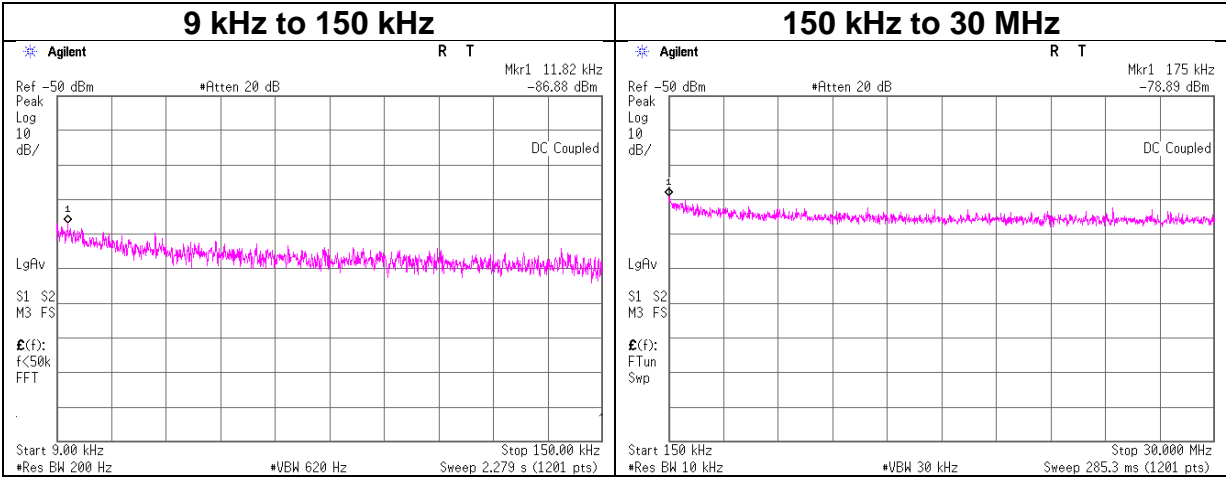
$E [dBuV/m] = EIRP [dBm] - 20 \log (Distance [m]) + Ground\ bounce [dB] + 104.8 [dBuV/m]$

$EIRP [dBm] = Reading [dBm] + Cable\ loss [dB] + Attenuator\ Loss [dB] + Antenna\ gain [dBi] + 10 * \log (N)$

N: Number of output

Conducted Spurious Emission

Test place Ise EMC Lab. No.8 Measurement Room
 Date March 24, 2025
 Temperature / Humidity 25 deg. C / 46 % RH
 Engineer Takeshi Hiyaji
 Mode Tx BT LE (2M-PHY) 2480 MHz



Frequency [kHz]	Reading [dBm]	Cable Loss [dB]	Attenuator Loss [dB]	Antenna Gain [dBi]	N (Number of Output)	EIRP [dBm]	Distance [m]	Ground bounce [dB]	E (field strength) [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
11.82	-86.9	0.10	9.8	2.9	1	-74.1	300	6.0	-12.8	46.1	58.9	
175.00	-78.9	0.10	9.8	2.9	1	-66.1	300	6.0	-4.8	22.7	27.5	

$E [dBuV/m] = EIRP [dBm] - 20 \log (Distance [m]) + Ground\ bounce [dB] + 104.8 [dBuV/m]$
 $EIRP [dBm] = Reading [dBm] + Cable\ loss [dB] + Attenuator\ Loss [dB] + Antenna\ gain [dBi] + 10 * \log (N)$
 N: Number of output

Power Density

Test place Ise EMC Lab. No.10 Measurement Room
Date April 11, 2025
Temperature / Humidity 23 deg. C / 50 % RH
Engineer Yuta Moriya
Mode Tx BT LE

BT LE 1M-PHY

Freq. [MHz]	Reading [dBm / 3 kHz]	Cable Loss [dB]	Atten. Loss [dB]	Result [dBm / 3 kHz]	Limit [dBm / 3 kHz]	Margin [dB]
2402	-16.85	0.55	9.73	-6.57	8.00	14.57
2442	-17.29	0.55	9.73	-7.01	8.00	15.01
2480	-17.31	0.56	9.73	-7.02	8.00	15.02

BT LE 2M-PHY

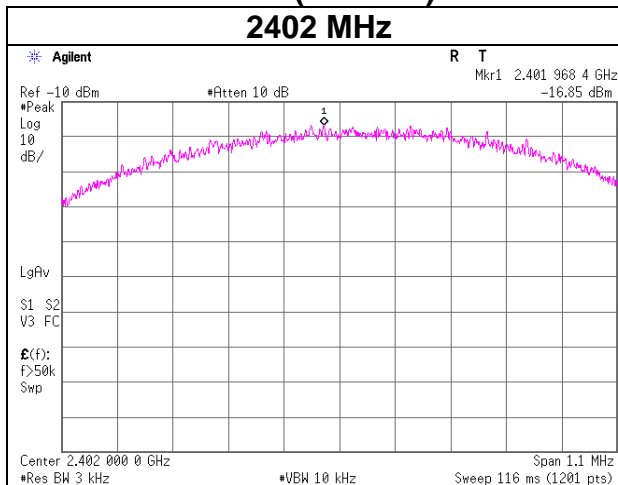
Freq. [MHz]	Reading [dBm / 3 kHz]	Cable Loss [dB]	Atten. Loss [dB]	Result [dBm / 3 kHz]	Limit [dBm / 3 kHz]	Margin [dB]
2402	-19.41	0.55	9.73	-9.13	8.00	17.13
2442	-20.01	0.55	9.73	-9.73	8.00	17.73
2480	-20.18	0.56	9.73	-9.89	8.00	17.89

Sample Calculation:

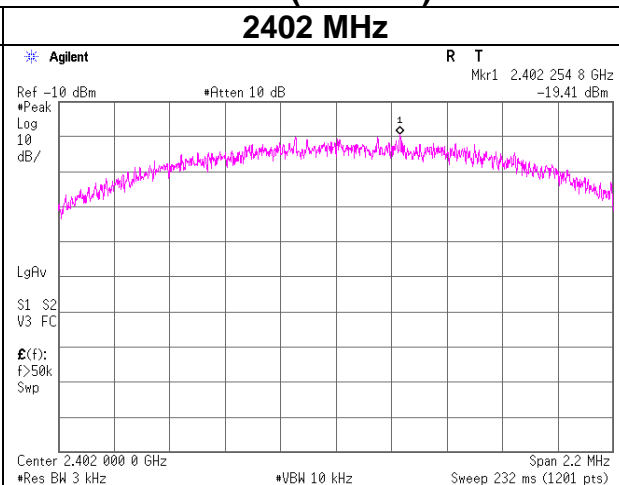
Result = Reading + Cable Loss (including the cable(s) customer supplied) + Attenuator Loss

Power Density

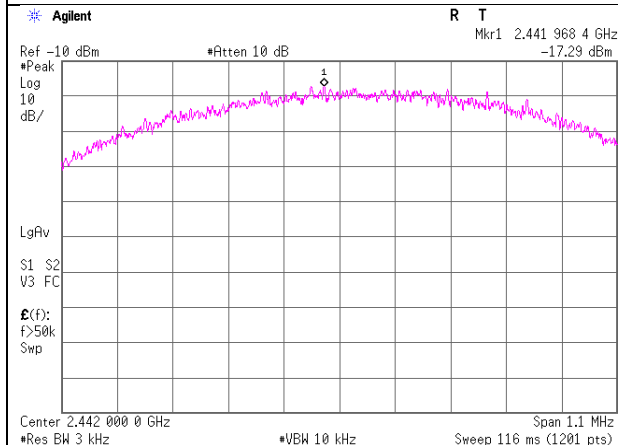
**BT LE(1M-PHY)
2402 MHz**



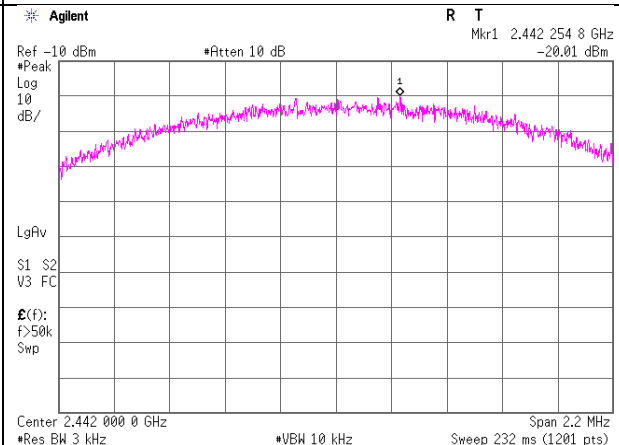
**BT LE(2M-PHY)
2402 MHz**



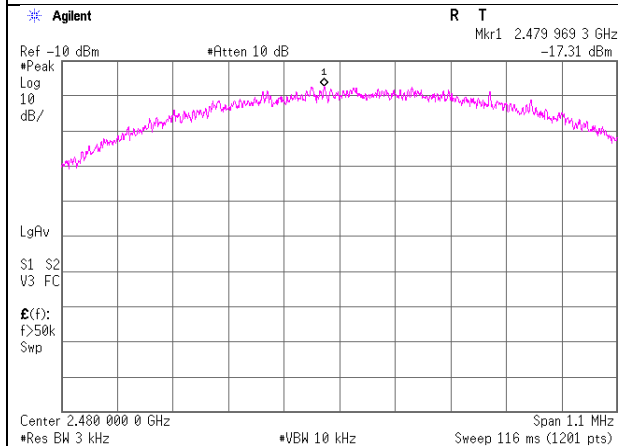
2442 MHz



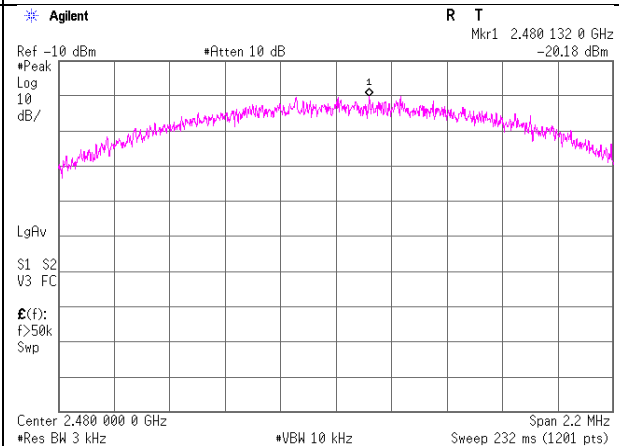
2442 MHz



2480 MHz



2480 MHz



APPENDIX 2: Test Instruments

Test Equipment (March 24 to April 11, 2025)

Test Item	LIMS ID	Description	Manufacturer	Model	Serial	Last Calibration Date	Cal Int
RE	141265	Logperiodic Antenna (200-1000MHz)	Schwarzbeck Mess-Elektronik OHG	VUSLP9111B	9111B-190	07/10/2024	12
RE	141296	High Pass Filter 3.5-18.0GHz	UL-ISE	HPF SELECTOR	002	09/11/2024	12
RE	141317	Coaxial Cable	UL-ISE	-	-	09/11/2024	12
RE	141331	Attenuator (6dB)	TME	UFA-01	-	02/19/2025	12
RE	141427	Biconical Antenna	Schwarzbeck Mess-Elektronik OHG	VHA9103B+ BBA9106	08031	07/30/2024	12
RE	141512	Horn Antenna 1-18GHz	Schwarzbeck Mess-Elektronik OHG	BBHA9120D	254	10/17/2024	12
RE	141513	Horn Antenna 15-40GHz	Schwarzbeck Mess-Elektronik OHG	BBHA9170	BBHA9170306	07/19/2024	12
RE	141542	Digital Tester	Fluke Corporation	FLUKE 26-3	78030611	08/06/2024	12
RE	141594	Pre Amplifier	Keysight Technologies Inc	8447D	2944A10150	02/19/2025	12
RE	141949	Test Receiver	Rohde & Schwarz	ESCI	100767	06/05/2024	12
RE	141978	Spectrum Analyzer	Keysight Technologies Inc	E4448A	MY46180899	05/09/2024	12
RE	142004	AC2_Semi Anechoic Chamber (NSA)	TDK	Semi Anechoic Chamber 3m	DA-06902	12/12/2023	24
RE	142006	AC2_Semi Anechoic Chamber (SVSWR)	TDK	Semi Anechoic Chamber 3m	DA-06902	04/17/2023	24
RE	142228	Measure, Tape, Steel	KOMELON	KMC-36	-	-	-
RE	178648	EMI measurement program	TSJ (Techno Science Japan)	TEPTO-DV	-	-	-
RE	238713	Double Ridge Horn Antenna	Schwarzbeck Mess-Elektronik OHG	BBHA 9120 C	688	09/02/2024	12
RE	244707	Thermo-Hygrometer	HIOKI E. E. CORPORATION	LR5001	231202102	01/19/2025	12
RE	252663	Microwave Cable	Huber+Suhner	SF126E/11PC35/ 11PC35/ 1000MM,5000MM	616276/126E / 616275/126E	09/10/2024	12
RE	253739	Pre Amplifier	Keysight Technologies Inc	8449B	3008A01919	10/23/2024	12
AT	141156	Attenuator (10dB)	Weinschel Corp	2	BL1173	11/11/2024	12
AT	141360	DIGITAL HiTESTER	HIOKI E. E. CORPORATION	3805	070900532	01/16/2025	12
AT	141419	Attenuator	Weinschel Associates	WA56-10	56100305	05/22/2024	12
AT	141809	Power Meter	Anritsu Corporation	ML2495A	825002	05/22/2024	12
AT	141814	Power Meter	Raditeq (Formerly DARE!! Instruments)	RPR3006W	14100048SNO 082	10/24/2024	12
AT	141830	Power sensor	Anritsu Corporation	MA2411B	738285	05/22/2024	12
AT	141900	Spectrum Analyzer	Keysight Technologies Inc	E4440A	MY46185823	11/13/2024	12
AT	141902	Spectrum Analyzer	Keysight Technologies Inc	E4440A	MY46187105	05/30/2024	12
AT	192348	Thermo-Hygrometer	Mother tool	MT-893	-	01/19/2025	12
AT	195231	Microwave Cable	Huber+Suhner	SF102D/11PC24/ 11PC24/1000mm	537062/126E	02/19/2025	12
AT	196430	Microwave Cable	Huber+Suhner	SF102D/11PC24/ 11PC24/1000mm	537059/126EA	02/20/2025	12
AT	197220	Microwave cable	Huber+Suhner	SF126E/11PC35/ 11PC35/2000MM	537003/126E	03/18/2025	12
AT	244711	Thermo-Hygrometer	HIOKI E. E. CORPORATION	LR5001	231202105	01/19/2025	12
AT	248893	Attenuator	Weinschel Associates	WA56-10-1112	2	05/28/2024	12

Test Equipment (September 10, 2025)

Test Item	LIMS ID	Description	Manufacturer	Model	Serial	Last Calibration Date	Cal Int
AT	244711	Thermo-Hygrometer	HIOKI E. E. CORPORATION	LR5001	231202105	01/19/2025	12
AT	141557	DIGITAL HiTESTER	HIOKI E. E. CORPORATION	3805	070900530	01/15/2025	12
AT	141809	Power Meter	Anritsu Corporation	ML2495A	825002	05/15/2025	12
AT	141830	Power sensor	Anritsu Corporation	MA2411B	738285	05/15/2025	12
AT	141419	Attenuator	Weinschel Associates	WA56-10	56100305	05/20/2025	12
AT	196430	Microwave Cable	Huber+Suhner	SF102D/11PC24/11 PC24/1000mm	537059/126EA	02/20/2025	12

*Hyphens for Last Calibration Date and Cal Int (month) are instruments that Calibration is not required (e.g. software), or instruments checked in advance before use.

The expiration date of the calibration is the end of the expired month.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

Test item:

AT: Antenna Terminal Conducted test
RE: Radiated Emission